## Notice of References Cited Application/Control No. 10/593,872 Examiner NATHANIEL J. LEE Applicant(s)/Patent Under Reexamination FUJITA ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2001/0000622 A1	05-2001	Reeh et al.	257/98
*	В	US-6,652,972 B1	11-2003	Conzone et al.	428/426
*	С	US-2005/0006659 A1	01-2005	Ng et al.	257/099
*	D	US-2002/0171911 A1	11-2002	Maegawa, Mamoru	359/308
*	Е	US-2004/0095063 A1	05-2004	Murazaki et al.	313/503
*	F	US-2005/0056055 A1	03-2005	Celikkaya et al.	065/017.4
	G	US-			
	Ι	US-			
	-	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.